Power MOSFET

60 V, 16.5 m Ω , 27 A, Single N-Channel

Features

- Low R_{DS(on)} to Minimize Conduction Losses
- Low Q_G and Capacitance to Minimize Driver Losses
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

MAXIMUM RATINGS (T_J = 25°C unless otherwise noted)

| Parameter | | Symbol | Value | Unit | |
|---|--|---------------------------|-----------------------------------|---------------|----|
| Drain-to-Source Voltage | | V_{DSS} | 60 | V | |
| Gate-to-Source Voltage | | | V_{GS} | ±20 | V |
| Continuous Drain Cur- | | $T_C = 25^{\circ}C$ | I _D | 27 | Α |
| rent R _{θJC} (Notes 1 & 3) | Steady | T _C = 100°C | | 19 | |
| Power Dissipation R _{θJC} | State | T _C = 25°C | P _D | 25 | W |
| (Note 1) | • | $T_C = 100^{\circ}C$ | | 12 | |
| Continuous Drain Cur- | Steady State | T _A = 25°C | I _D | 10 | Α |
| rent $R_{\theta JA}$ (Notes 1, 2 & 3) | | T _A = 100°C | | 7.2 | |
| Power Dissipation R _{θJA} | | T _A = 25°C | P_{D} | 3.6 | W |
| (Notes 1 & 2) | | T _A = 100°C | | 1.8 | |
| Pulsed Drain Current | $T_A = 25^{\circ}$ | C, t _p = 10 μs | I _{DM} | 130 | Α |
| Operating Junction and S | Operating Junction and Storage Temperature | | T _J , T _{stg} | -55 to 175 | ç |
| Source Current (Body Diode) | | | I _S | 28 | Α |
| Single Pulse Drain–to–Source Avalanche Energy ($T_J = 25^{\circ}C$, $I_{L(pk)} = 2.0 \text{ A}$) | | | E _{AS} | 93 | mJ |
| Lead Temperature for Sol (1/8" from case for 10 s) | dering Pu | rposes | TL | 260 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

THERMAL RESISTANCE MAXIMUM RATINGS

| Parameter | Symbol | Value | Unit |
|---|-----------------|-------|------|
| Junction-to-Case (Drain) (Note 1) | $R_{\theta JC}$ | 6.0 | °C/W |
| Junction-to-Ambient - Steady State (Note 2) | $R_{	heta JA}$ | 41 | |

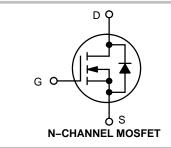
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface–mounted on FR4 board using a 650 mm², 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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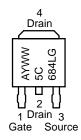
| V _{(BR)DSS} | V _{(BR)DSS} R _{DS(on)} | | |
|----------------------|--|------|--|
| 60 V | 16.5 mΩ @ 10 V | 27 A | |
| | 24.3 mΩ @ 4.5 V | 21 A | |





DPAK CASE 369C STYLE 2

MARKING DIAGRAM & PIN ASSIGNMENT



A = Assembly Location

Y = Year
WW = Work Week
5C684L = Device Code
G = Pb-Free Package

ORDERING INFORMATION

See detailed ordering and shipping information in the package dimensions section on page 5 of this data sheet.

ELECTRICAL CHARACTERISTICS ($T_J = 25^{\circ}C$ unless otherwise noted)

| Parameter | Symbol | Test Cond | lition | Min | Тур | Max | Unit |
|--|--------------------------------------|--|-------------------------|-----|------|------|-------|
| OFF CHARACTERISTICS | | | | | • | • | • |
| Drain-to-Source Breakdown Voltage | V _{(BR)DSS} | V _{GS} = 0 V, I _D : | = 250 μΑ | 60 | | | V |
| Drain-to-Source Breakdown Voltage Temperature Coefficient | V _{(BR)DSS} /T _J | | | | 27 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{GS} = 0 V, | T _J = 25°C | | | 10 | μΑ |
| | | $V_{DS} = 60 \text{ V}$ | T _J = 125°C | | | 250 | 1 |
| Gate-to-Source Leakage Current | I _{GSS} | $V_{DS} = 0 \text{ V}, V_{G}$ | is = 20 V | | | 100 | nA |
| ON CHARACTERISTICS (Note 4) | | | | | | | |
| Gate Threshold Voltage | V _{GS(TH)} | $V_{GS} = V_{DS}, I_{D}$ | _ = 20 μΑ | 1.2 | | 2.1 | V |
| Negative Threshold Temperature Coefficient | V _{GS(TH)} /T _J | | | | 4.5 | | mV/°C |
| Drain-to-Source On Resistance | R _{DS(on)} | V _{GS} = 10 V, I _I | _D = 15 A | | 13.7 | 16.5 | mΩ |
| | | V _{GS} = 4.5 V, I | _D = 15 A | | 19.4 | 24.3 | 1 |
| Forward Transconductance | 9FS | V _{DS} = 5.0 V, I | _D = 15 A | | 30 | | S |
| CHARGES, CAPACITANCES AND GATE RE | SISTANCES | | | | | | |
| Input Capacitance | C _{iss} | | | | 700 | | pF |
| Output Capacitance | C _{oss} | $V_{GS} = 0 \text{ V, f} = V_{DS} = 20 \text{ V}$ | | | 300 | | 1 |
| Reverse Transfer Capacitance | C _{rss} | VDS - 20 | <i>5</i> v | | 13 | | |
| Total Gate Charge | Q _{G(TOT)} | V _{DS} = 30 V, | V _{GS} = 4.5 V | | 4.6 | | nC |
| | | $I_D = 15 \text{ A}$ | V _{GS} = 10 V | | 9.6 | | 1 |
| Threshold Gate Charge | Q _{G(TH)} | | • | | 1.2 | | nC |
| Gate-to-Source Charge | Q_{GS} | Vcs = 4.5 V. V. | ne = 30 V. | | 2.0 | | |
| Gate-to-Drain Charge | Q_{GD} | $V_{GS} = 4.5 \text{ V}, V_{DS} = 30 \text{ V},$ $I_{D} = 15 \text{ A}$ | | | 1.2 | | 1 |
| Plateau Voltage | V_{GP} | | | | 2.9 | | V |
| SWITCHING CHARACTERISTICS (Note 5) | | | | | • | • | • |
| Turn-On Delay Time | t _{d(on)} | | | | 8.0 | | ns |
| Rise Time | t _r | $V_{GS} = 4.5 \text{ V}, V_{I}$ | ne = 30 V. | | 43 | | |
| Turn-Off Delay Time | t _{d(off)} | $I_{D} = 15 \text{ A}, R_{G}$ | $= 2.5 \Omega$ | | 25 | | 1 |
| Fall Time | t _f | | | | 40 | | 1 |
| DRAIN-SOURCE DIODE CHARACTERISTIC | S | | | | | | |
| Forward Diode Voltage | V_{SD} | V _{GS} = 0 V, | T _J = 25°C | | 0.9 | 1.2 | V |
| | | $I_{S} = 15 \text{ A}$ | T _J = 125°C | | 0.8 | | 1 |
| Reverse Recovery Time | t _{RR} | | 1 - | | 20 | | ns |
| Charge Time | ta | $V_{GS} = 0 \text{ V, } dl_{S}/dt = 100 \text{ A/}\mu\text{s,}$ $l_{S} = 15 \text{ A}$ | | | 10 | | 1 |
| Discharge Time | tb | | | | 10 | | 1 |
| Reverse Recovery Charge | Q _{RR} | | | | 10 | | nC |

Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

TYPICAL CHARACTERISTICS

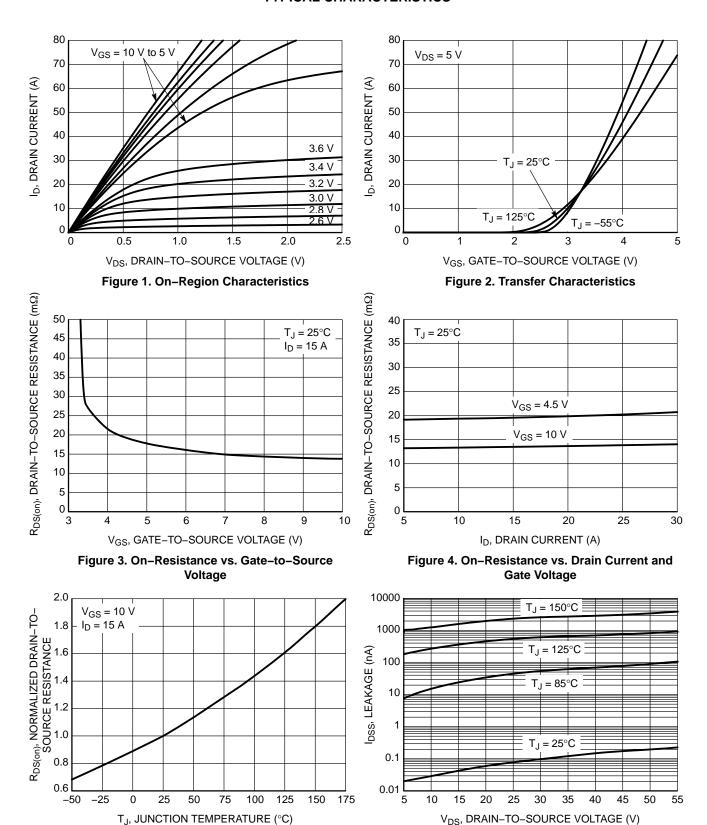


Figure 6. Drain-to-Source Leakage Current

vs. Voltage

Figure 5. On-Resistance Variation with

Temperature

TYPICAL CHARACTERISTICS

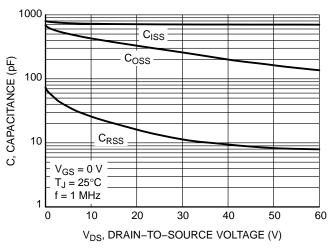


Figure 7. Capacitance Variation

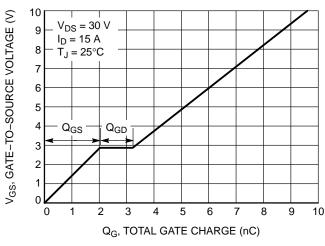


Figure 8. Gate-to-Source vs. Total Charge

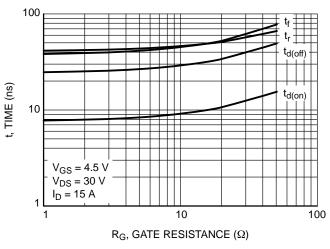


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

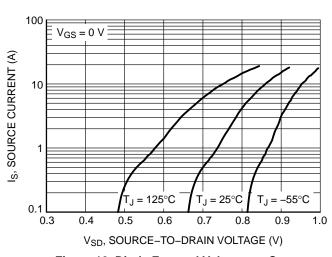


Figure 10. Diode Forward Voltage vs. Current

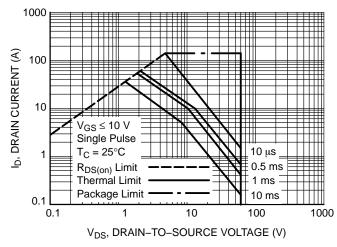


Figure 11. Maximum Rated Forward Biased Safe Operating Area

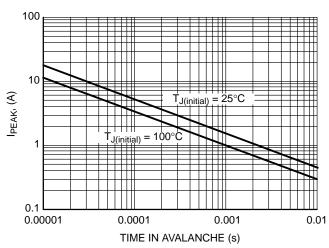


Figure 12. Maximum Drain Current vs. Time in Avalanche

TYPICAL CHARACTERISTICS

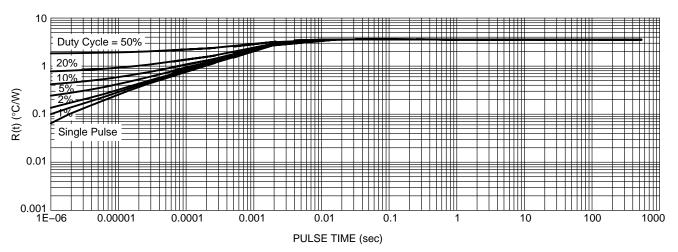


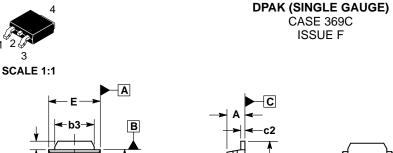
Figure 13. Thermal Response

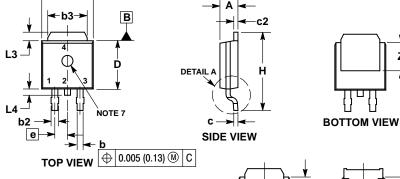
ORDERING INFORMATION

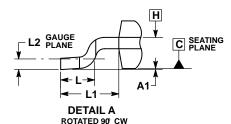
| Order Number | Package | Shipping [†] |
|---------------|-------------------|-----------------------|
| NTD5C684NLT4G | DPAK (Pb-Free) | 2500 / Tape & Reel |

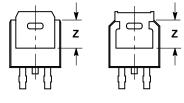
[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

DATE 21 JUL 2015





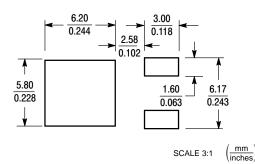




BOTTOM VIEW ALTERNATE CONSTRUCTIONS

| STYLE 1: PIN 1. BASE 2. COLLE 3. EMITTI 4. COLLE | ER 3. SOL | AIN 2. CATI JRCE 3. ANO | HODE 2. ANODE DE 3. GATE | STYLE 5: PIN 1. GATE 2. ANODE 3. CATHODE 4. ANODE |
|--|--------------|----------------------------|-----------------------------|---|
| STYLE 6: | STYLE 7: | 3. ANODE | STYLE 9: | STYLE 10: |
| PIN 1. MT1 | PIN 1. GATE | | PIN 1. ANODE | PIN 1. CATHODE |
| 2. MT2 | 2. COLLECTOR | | 2. CATHODE | 2. ANODE |
| 3. GATE | 3. EMITTER | | 3. RESISTOR ADJUST | 3. CATHODE |
| 4. MT2 | 4. COLLECTOR | | 4. CATHODE | 4. ANODE |

SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

NOTES:

z

- IOTES. 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994. 2. CONTROLLING DIMENSION: INCHES. 3. THERMAL PAD CONTOUR OPTIONAL WITHIN DI-

- MENSIONS b3, L3 and Z.

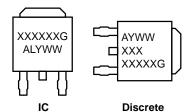
 Jimensions b And E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.006 INCHES PER SIDE.

 MENSIONS D AND E ARE DETERMINED AT THE
- OUTERMOST EXTREMES OF THE PLASTIC BODY.

 6. DATUMS A AND B ARE DETERMINED AT DATUM
- 7. OPTIONAL MOLD FEATURE.

| | | INC | HES | MILLIM | IETERS |
|---|-----|-------|-------|--------|--------|
| | DIM | MIN | MAX | MIN | MAX |
| | Α | 0.086 | 0.094 | 2.18 | 2.38 |
| | A1 | 0.000 | 0.005 | 0.00 | 0.13 |
| | b | 0.025 | 0.035 | 0.63 | 0.89 |
| ĺ | b2 | 0.028 | 0.045 | 0.72 | 1.14 |
| | b3 | 0.180 | 0.215 | 4.57 | 5.46 |
| | С | 0.018 | 0.024 | 0.46 | 0.61 |
| | c2 | 0.018 | 0.024 | 0.46 | 0.61 |
| | D | 0.235 | 0.245 | 5.97 | 6.22 |
| | Е | 0.250 | 0.265 | 6.35 | 6.73 |
| | е | 0.090 | BSC | 2.29 | BSC |
| | Н | 0.370 | 0.410 | 9.40 | 10.41 |
| | L | 0.055 | 0.070 | 1.40 | 1.78 |
| | L1 | 0.114 | REF | 2.90 | REF |
| ĺ | L2 | 0.020 | BSC | 0.51 | BSC |
| | L3 | 0.035 | 0.050 | 0.89 | 1.27 |
| | L4 | | 0.040 | | 1.01 |
| | Z | 0.155 | | 3.93 | |

GENERIC MARKING DIAGRAM*



XXXXXX = Device Code = Assembly Location Α L = Wafer Lot Υ = Year

WW = Work Week G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking.

| DOCUMENT NUMBER: | 98AON10527D | E |
|------------------|-------------------------------|---------|
| STATUS: | ON SEMICONDUCTOR STANDARD | a ve |
| NEW STANDARD: | REF TO JEDEC TO-252 | "(|
| DESCRIPTION: | DPAK SINGLE GAUGE SURFACE MOU | NT |

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PAGE 1 OF 2



| DOCUMENT | NUMBER: |
|-----------------|---------|
| 98AON10527 | 7D |

PAGE 2 OF 2

| ISSUE | REVISION | DATE |
|-------|--|-------------|
| 0 | RELEASED FOR PRODUCTION. REQ. BY L. GAN | 24 SEP 2001 |
| Α | ADDED STYLE 8. REQ. BY S. ALLEN. | 06 AUG 2008 |
| В | ADDED STYLE 9. REQ. BY D. WARNER. | 16 JAN 2009 |
| С | ADDED STYLE 10. REQ. BY S. ALLEN. | 09 JUN 2009 |
| D | RELABELED DRAWING TO JEDEC STANDARDS. ADDED SIDE VIEW DETAIL A. CORRECTED MARKING INFORMATION. REQ. BY D. TRUHITTE. | 29 JUN 2010 |
| E | ADDED ALTERNATE CONSTRUCTION BOTTOM VIEW. MODIFIED DIMENSIONS b2 AND L1. CORRECTED MARKING DIAGRAM FOR DISCRETE. REQ. BY I. CAMBALIZA. | 06 FEB 2014 |
| F | ADDED SECOND ALTERNATE CONSTRUCTION BOTTOM VIEW. REQ. BY K. MUSTAFA. | 21 JUL 2015 |
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